

SCOPE: +5V to \pm 10V CMOS SWITCHED-CAPACITOR VOLTAGE CONVERTER

Device Type 01	Generic Number MAX680(x)/883B	SMD Number 5962-93120
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Case Outline(s). The case outlines shall be designated in Mil-Std-1835 and as follows:

Outline Letter Maxim SMD JA P	Mil-Std-1835 GDIP1-T08 or CDIP2-T08	Case Outline 8 LEAD CERDIP	Package Code J08
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Absolute Maximum Ratings

Voltage Referenced to V⁻

V _{CC} to GND	+6.2V
V ⁺	+12V
V ⁻	-12V
V- Short-circuit Current Duration	Continuous
V ⁺ Current	75mA
V _{CC} Δ V/ Δ T	1V/ μ s

Lead Temperature (soldering, 10 seconds)

+300°C

Storage Temperature

-65°C to +150°C

Continuous Power Dissipation

T_A=+70°C

8 lead CERDIP(derate 8.0mW/ $^{\circ}$ C above +70°C)

640mW

Junction Temperature T_J

+150°C

Thermal Resistance, Junction to Case, Θ JC:

Case Outline 8 lead CERDIP..... 55°C/W

Thermal Resistance, Junction to Ambient, Θ JA:

Case Outline 8 lead CERDIP..... 125°C/W

Recommended Operating Conditions

Ambient Operating Range (T_A)

-55°C to +125°C

Input Voltage Range (V_{CC}), R_L=10k Ω

+2.0V dc to +6.0V dc

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TABLE 1. ELECTRICAL TESTS:

TEST	Symbol	CONDITIONS $-55^{\circ}\text{C} \leq T_{\text{A}} \leq +125^{\circ}\text{C}$ Unless otherwise specified	Group A Subgroup	Device type	Limits Min	Limits Max	Units
Supply Voltage Range	V _{CC}	R _L =10kΩ	1,2,3	All	2	6	V
Supply Current	I _{CC}	V _{CC} =3V, R _L =∞	1	All		1	mA
		V _{CC} =5V, R _L =∞	1 2,3			2 3	
Positive Charge-Pump Output Source Resistance	R _{OUT+}	I _{L+} =5mA, I _{L-} =0mA, V _{CC} =2.8V	1	All		300	Ω
		I _{L+} =10mA, I _{L-} =0mA, V _{CC} =5V	1 2,3			250 400	
Negative Charge-Pump Output Source Resistance	R _{OUT-}	I _{L-} =5mA, I _{L+} =0mA, V+=5.6V	1	All		175	Ω
		I _{L-} =10mA, I _{L+} =0mA, V+=10V	1 2,3			150 250	
Oscillator Frequency	f _{osc}		1	All	4		kHz
Voltage Conversion Efficiency	V _{EFF}	V+, R _L =∞	1	All	95		%
		V-, R _L =∞			90		

Package	ORDERING INFORMATION:	SMD Number
8 pin CERDIP	MAX680MJA/883B	5962-9312001MPA

TERMINAL CONNECTIONS:

	J8
1	C-
2	C2+
3	C2-
4	V-
5	GND
6	V _{CC}
7	C1+
8	V+

QUALITY ASSURANCE

Sampling and inspection procedures shall be in accordance with MIL-Prf-38535, Appendix A as specified in Mil-Std-883.

Screening shall be in accordance with Method 5004 of Mil-Std-883. Burn-in test Method 1015:

1. Test Condition, A, B, C, or D.
2. TA = +125°C minimum.
3. Interim and final electrical test requirements shall be specified in Table 2.

Quality conformance inspection shall be in accordance with Method 5005 of Mil-Std-883, including Groups A, B, C, and D inspection.

Group A inspection:

1. Tests as specified in Table 2.
2. Selected subgroups in Table 1, Method 5005 of Mil-Std-883 shall be omitted.

Group C and D inspections:

- a. End-point electrical parameters shall be specified in Table 1.
- b. Steady-state life test, Method 1005 of Mil-Std-883:
 1. Test condition A, B, C, D.
 2. TA = +125°C, minimum.
 3. Test duration, 1000 hours, except as permitted by Method 1005 of Mil-Std-883.

TABLE 2. ELECTRICAL TEST REQUIREMENTS

Mil-Std-883 Test Requirements	Subgroups per Method 5005, Table 1
Interim Electric Parameters Method 5004	1
Final Electrical Parameters Method 5005	1*, 2, 3
Group A Test Requirements Method 5005	1, 2, 3
Group C and D End-Point Electrical Parameters Method 5005	1

* PDA applies to Subgroup 1 only.